INFORMATION DISCLOSURE CITATION				Atty Docket: 061450/0304609		Serial No.	
PTO-1449				FID-101-D5 to be assigned Applicant: S. Prakash			
Submitted: July 3, 2003				Filing Date: Herewith		Prior Group Art Unit: 2856	
		IJ###DU:S	PATENT	APPLICATIONS			
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME		CLASS	S SUBCLASS	FILING DATE
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1	5,763,768	06/1998	Henderso	Henderson, et al.		105	
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INITIALS	PATENT NO.	DATE		COUNTRY		S SUBCLASS	
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I WWW. SIE	IN OTHER DOC	MENTS (Incl	iuding Av	ilhor, Tille, Date, Pertin	ient(Pägi	es;(Etc.))	
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K	Conducting tops" (J. Vac. Sci. Tech. A 13(3), May/June 1995, pp. 1699-1704						
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EXAMINER	RA EVI)		DATE CONSIDERED	2.	- 5-0	4

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance <u>and</u> not considered. Include copy of this form with next communication to applicant.